



Ottawa  
Section



**Seminar by IEEE Ottawa Section I&M Society Chapter  
In conjunction with IEEE Ottawa Section PES/RS Chapters, EA, and EPMG of INMS/NRC**

*The IEEE Ottawa Section, with Electrical Power Measurements Group of NRC, is organizing a workshop on Instrumentation & Measurements for IEEE members. Non-members interested in the subject are also welcome.*

## **The Future of Instrumentation and Measurement Today's Trends and Future Directions**

Speakers from Industry, Research Institutions and Academia

**DATE:** Wednesday, February 22, 2006

**TIME:** Registration, Networking, and Coffee/Pastry: 8:00 - 8:30 a.m.; Workshop: 8:30 am – 4:30 pm  
Buffet Lunch 12:10 p.m. – 1:00 p.m. Coffee breaks 10:10 – 10:25 a.m. and 2:20 – 2:35 p.m.

**PLACE:** National Research Council, 1200 Montreal Road, Ottawa, Building M-50, Auditorium.

**PARKING:** No fee at the visitor's parking. Please respect restricted areas.

### **Presentations/Speakers**

- Moderator: Gerry Turcotte, former Communications Research Centre President,
- *Opening Address* "**Metrology - the art and science of measurement**", by Dr. James McLaren, Director General, Institute for National Measurement Standards, NRC,
- *Keynote Address* "**Intelligent Sensor Agents for Infrastructure and Environment Monitoring - Challenges**", by Dr. Emil Petriu, Acting Dean, Faculty of Engineering, University of Ottawa,
- **I&M Industry Trends**, by Larry Desjardin, Strategic Planning Manager, Agilent Technologies, Santa Rosa, CA
- **Embedded Testing of VLSI / Systems on a Chip**, by Jeff Rearick, Scientist, Agilent Technologies, Fort Collins, CO,
- **Optical Heterodyne Instruments in Optical Communications**, by Dr. Bogdan Szafraniec, Agilent Technologies, Palo Alto, CA,
- **Microwave antenna measurement at CRC**, by David Lee, Advanced Antenna Technology Research Group, Communications Research Centre of Canada,
- **Fast and Selective Detection of Chemical and Biological Agents using Ion Mobility and Mass Spectrometry**, by Dr. Zoltan Mester, Institute for National Measurement Standards, National Research Council of Canada,
- **LXI Interface Standard / Synthetic Instruments**, by Grant Drenkow, Solution Planner, System Components, Agilent Technologies, Loveland, CO,
- **Military Applications of High Performance Data Acquisition and Signal Processing Systems**, by Robert Inkol, Defense Research and Development Canada,

**Attend this IEEE Workshop and Earn 0.65 CEUs !**

**- Continuing Education Units as evaluated by the [Engineering Institute of Canada](#) -**

### **Admission:**

*Special Discount for IEEE I&M Society Members:* \$20

IEEE/IEE/PEO Members: \$80 Members Retired / Job Seekers: \$40.00 IEEE/IEE Student Memb.: \$20  
Non-members: \$100.00 Non-members Retired / Job Seekers: \$50.00 Non-members Students: \$25.00  
Registration at the door: additional \$10. Buffet Lunch and refreshments included in the registration.

**To ensure a seat, please register on-line at:**

[http://www.modasolutions.com/Forms/IEEE\\_EDUCATION/index19012006.htm](http://www.modasolutions.com/Forms/IEEE_EDUCATION/index19012006.htm)